Global Foundries MOOV

No	ITEM	SPEC	RESULT
1	Resolution (0.175um IsoLine) Conv NA/σ = 0.68/0.75	Customer Dependent based on CD Tolerance, SEM/15 Point in Field, V/H 0.175um Iso	Customer needs to calculate using Item2 DOF Data
2	DOF (0.175um IsoLine) Conv NA/σ = 0.68/0.75	Customer Dependent based on CD Tolerance, SEM/15 Point in Field, V/H 0.175um Iso	Customer needs to calculate
3	Linewidth Abnormality/COMA (0.175um L&S) Conv NA/σ = 0.68/0.44	[(L1 – L5) / (L1 + L5)] SEM/15 Point in Field, V/H 0.175um Iso	0.063 um
4	Total Focus Deviation Conv NA/σ = 0.68/0.75	(0.25µm L&S / 15Point V/H) Max-Min ≤ 0.20µm	0.222µm
5	Lens Astigmatisim Conv NA/σ = 0.68/0.75	(0.25µm L&S / 15Point V/H) |V-H| ≤ 0.20µm	0.119µm
6	Lens Dynamic Distortion Conv NA/σ = 0.68/0.75	X,Y = Within ±25nm	X = 12nm~57nm Y = -19nm~59nm
7	Lens Flare / IU Flare Conv NA/σ = 0.68/0.75	Customer Dependent	Lens Flare = 8.2% IU Flare = 1.54%
8	Wafer Flatness Accuracy	1) Flat Within ≥ Max-Min 3.0µm 2) L.F.S Within ≥ Max-Min 0.8µm	1. 1.41µm 2. 0.470µm
9	Exposure Power Conv NA/σ = 0.68/0.75	Within ≥ 700mW/cm2	528.71mW/cm2
10	Illumination Uniformity Conv NA/σ = 0.68/0.75	Within ±2%	1.5%
11	Orthogonality Accuracy	Within ± 0.48urad	±0.20urad
12	Stage Precision Accuracy 1) Stepping Accuracy 2) Backlash Accuracy	1) 3σ ≤ 25nm 2) 3σ ≤ 25nm	1. X: 14, 17, 18 Y: 14, 19, 15 2. X: 21, 20, 20 Y: 25, 25, 25
13	Wafer Pre-Alignment Repeatability	3σ≦15µm	X : 4.345 µm Y : 5.915 µm T : 6.280 µm

No	ITEM	SPEC	RESULT
14	Synchronization Accuracy 1) Mean 2) MSD	1) ≦10nm(-5nm ~ +5nm) 2) ≦ 25nm	1). X : 10nm, Y : 10nm 2). X : 24nm, Y : 14nm
15	AF Adjustment Result	PSD Max – Min ≤ 0.2μm	0.058μm
16	Integrator Accuracy	Target: 10, 20, 50, 100, 200mj/cm2 Ave ≤ 1.3%	Ave Max = 0.32%
17	Alignment Accuracy 1) FIA-EGA 2) LSA-EGA	FIA-EGA = |M| + 3σ ≤ 35nm LSA-EGA = |M| + 3σ ≤ 40nm	1) X = ±20nm Y = ±20nm 2) X= ±15nm Y = ±15nm